# **Power MOSFET**

# 30 V, 57 A, Single N-Channel, SO-8 FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Device

### **Applications**

- CPU Power Delivery
- DC-DC Converters

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#### **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

Para	Symbol	Value	Unit		
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Vol-	Gate-to-Source Voltage				V
Continuous Drain Current R <sub>0.1A</sub>		T <sub>A</sub> = 25°C	I <sub>D</sub>	13.1	Α
(Note 1)		$T_A = 85^{\circ}C$		9.5	
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.17	W
Continuous Drain		T <sub>A</sub> = 25°C	ID	8.3	Α
Current R <sub>θJA</sub> (Note 2)	Steady	T <sub>A</sub> = 85°C		6	
Power Dissipation R <sub>θJA</sub> (Note 2)	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	0.87	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	57	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C		41	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	41.7	W
Pulsed Drain Current	t <sub>p</sub> =10μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	115	Α
Operating Junction a Temperature	T <sub>J</sub> , T <sub>STG</sub>	–55 to +150	°C		
Source Current (Boo	I <sub>S</sub>	35	Α		
Drain to Source dV/d	dV/dt	6	V/ns		
Single Pulse Drain–to–Source Avalanche Energy ( $V_{DD}$ = 30 V, $V_{GS}$ = 10 V, $I_{L}$ = 19 $A_{pk}$ , $L$ = 1.0 mH, $R_{G}$ = 25 $\Omega$ )			EAS	180	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

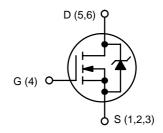
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



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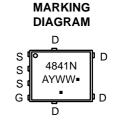
#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	7.0 mΩ @ 10 V	57 A
	11.4 mΩ @ 4.5 V	57 A



**N-CHANNEL MOSFET** 





A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTMFS4841NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4841NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

May, 2006 - Rev. 0

<sup>\*</sup>For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	57.7	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	143.4	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS				•		•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				25		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$	T <sub>J</sub> = 25 °C			1	
		V <sub>DS</sub> = 24 V	T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.5		2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.6		mV/°
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V to}$	I <sub>D</sub> = 30 A		4.7	7.0	†
		11.5 V	I <sub>D</sub> = 15 A		4.6		1
	V <sub>GS</sub> = 4.5 \	V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		9.2	11.4	mΩ
			I <sub>D</sub> = 15 A		8.5		
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 15 A			16		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>	$V_{GS} = 0 \text{ V, } f = 1 \text{ MHz, } V_{DS} = 12 \text{ V}$			1436		pF
Output Capacitance	C <sub>OSS</sub>				348		
Reverse Transfer Capacitance	C <sub>RSS</sub>				177		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			11.5	17	nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				2.0		
Gate-to-Source Charge	Q <sub>GS</sub>				5.0		
Gate-to-Drain Charge	$Q_{GD}$				5.1		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 11.5 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A			25.4		nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t <sub>d(ON)</sub>				13.5		
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			66.5		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				15.5		
Fall Time	t <sub>f</sub>				7.5		
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			8.1		ns
Rise Time	t <sub>r</sub>				24.2		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				22.8		
Fall Time	t <sub>f</sub>				5.7		

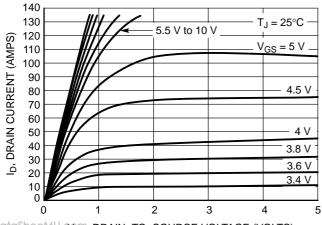
- 3. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

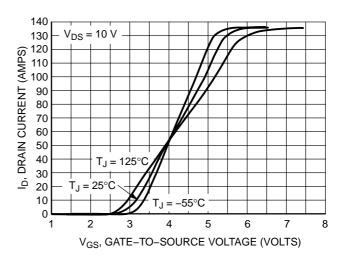
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
DRAIN-SOURCE DIODE CHARACTERISTICS								
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 V$	T <sub>J</sub> = 25°C		0.9	1.2	.,	
		$V_{GS} = 0 V$ , $I_S = 30 A$	T <sub>J</sub> = 125°C		0.8		V	
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dl <sub>S</sub> /dt = 100 A/μs,			20.5		ns	
Charge Time	t <sub>a</sub>				11.6			
Discharge Time	t <sub>b</sub>	$V_{GS} = 0 \text{ V, dl}_S/\text{dt} = 100 \text{ A/}\mu\text{s,}$ $I_S = 30 \text{ A}$			8.9		1	
Reverse Recovery Charge	Q <sub>RR</sub>				10.7		nC	
PACKAGE PARASITIC VALUES								
Source Inductance	L <sub>S</sub>				0.93		nH	
Drain Inductance	L <sub>D</sub>	T <sub>A</sub> = 25°C 0.005 1.84			0.005			
Gate Inductance	L <sub>G</sub>					1		
Gate Resistance	$R_{G}$	3.2					Ω	

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

#### TYPICAL PERFORMANCE CURVES



 $www. \texttt{DataSheet4U}. \texttt{CV}_{\texttt{DS}}^{\texttt{rog}}, \texttt{DRAIN-TO-SOURCE} \texttt{ VOLTAGE} \texttt{ (VOLTS)}$ 



**Figure 2. Transfer Characteristics** 



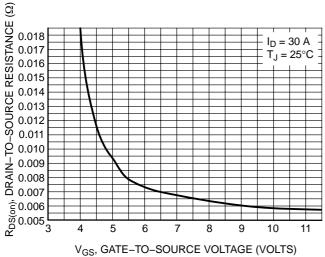


Figure 3. On-Resistance vs. Gate-to-Source Voltage

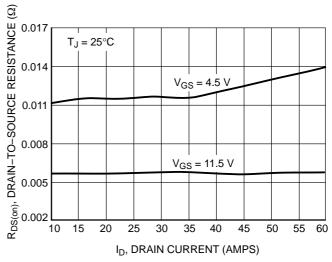


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

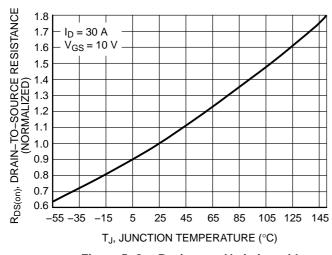


Figure 5. On–Resistance Variation with Temperature

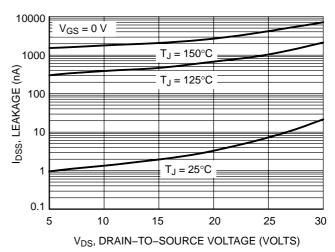
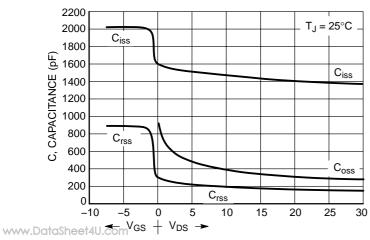


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### TYPICAL PERFORMANCE CURVES

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GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (VOLTS) 11 10 9 8 7 6 5  $Q_{\underline{G}\underline{D}}$ Q<sub>GS</sub> 4  $V_{DD} = 15 V$ 3  $V_{GS} = 11.5 \text{ V}$ 2  $I_D = 30 A$  $T_J = 25^{\circ}C$ 2 12 14 16 18 20 0 10 22 24 26 Q<sub>G</sub>, TOTAL GATE CHARGE (nC)

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



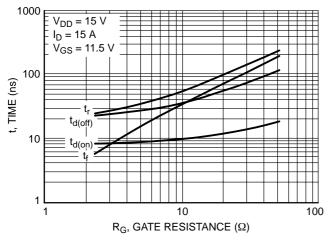


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

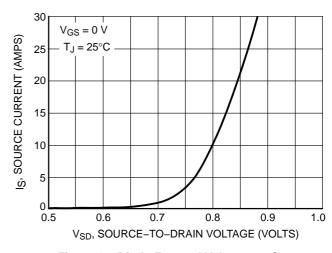


Figure 10. Diode Forward Voltage vs. Current

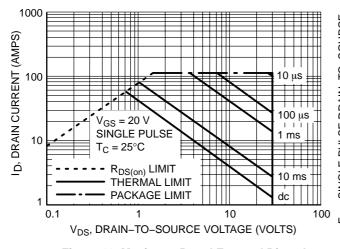


Figure 11. Maximum Rated Forward Biased Safe Operating Area

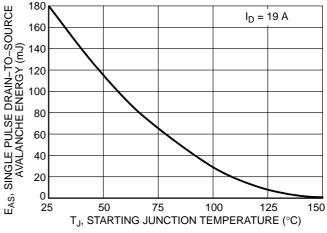
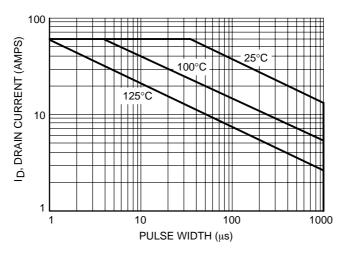


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

# **TYPICAL PERFORMANCE CURVES**



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Figure 13. EAS vs. Pulse Width

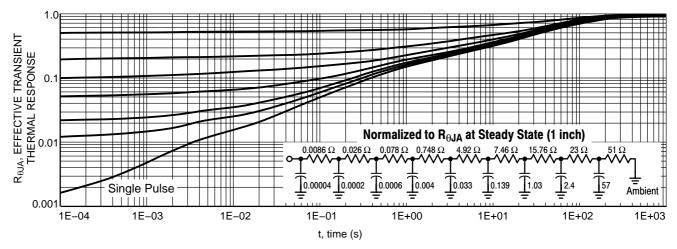
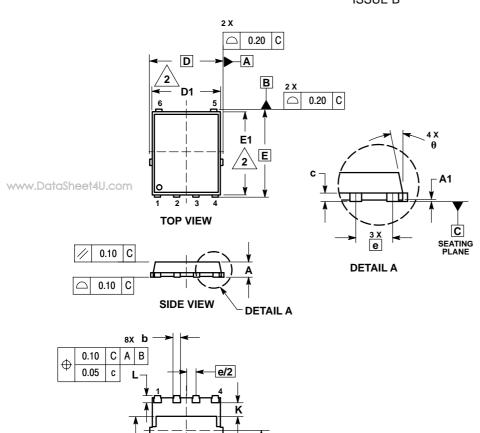


Figure 14. FET Thermal Response

#### PACKAGE DIMENSIONS

#### SO-8 FLAT LEAD (DFN6) CASE 488AA-01 **ISSUE B**



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE **BURRS**

	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	0.90	0.99	1.20			
A1	0.00		0.05			
b	0.33	0.41	0.51			
С	0.23	0.28	0.33			
D		5.15 BSC	;			
D1	4.50	4.90	5.10			
D2	3.50		4.22			
E	6.15 BSC					
E1	5.50	5.80	6.10			
E2	3.45		4.30			
е		1.27 BSC				
G	0.51	0.61	0.71			
K	0.51					
L	0.51	0.61	0.71			
L1	0.05	0.17	0.20			
M	3.00	3.40	3.80			
θ	0 °		12 °			

STYLE 1: PIN 1. SOURCE 2. SOURCE

- 3. SOURCE 4. GATE
- 5. DRAIN
- 6. DRAIN

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